



Fabricating a ZnO Piezoelectric Pressure Sensor

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Piezoelectric response **CONFIRMED**

— April 21, 2026

- Our device has **confirmed piezoelectric response**
- Signal **passed three independent controls** (triboelectric, polarity, and mechanical-coupling null tests)



Motivation:

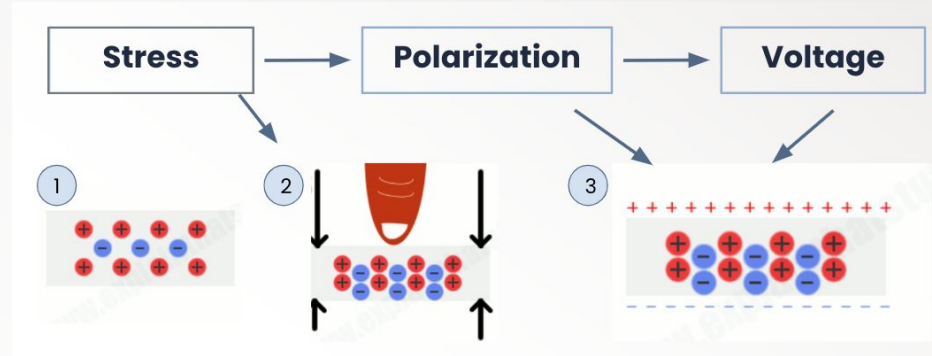
Why measure
pressure/impact?

Need: convert mechanical events
(pressure changes/impact) into a
measurable electric signals

Piezoelectric: converts applied stress into
voltage/charge

Applications:

- concussion monitors (monitor pressure or mechanical contact)
- structural health (stress and damage)
- Robotics (touch sensing)



ZnO Thin Films

ZnO is **wurtzite and non-centrosymmetric**

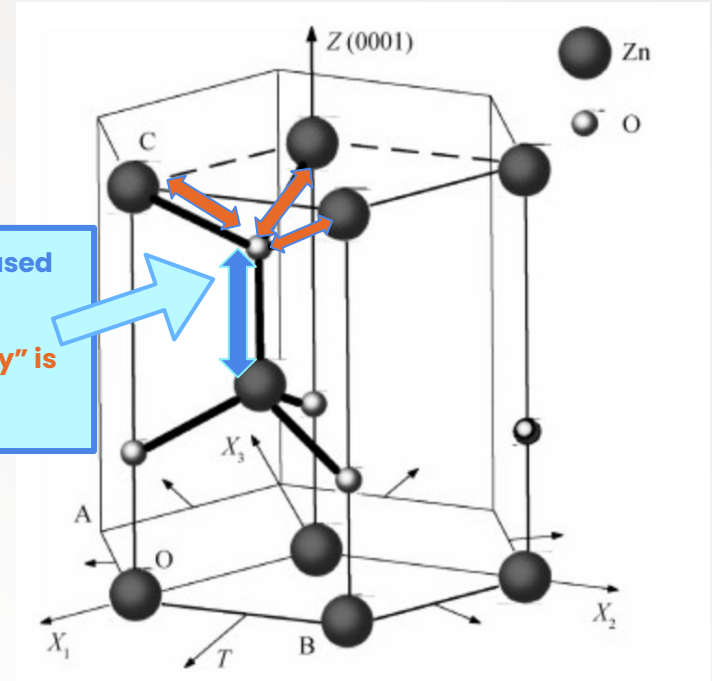
Lacks inversion symmetry $\rightarrow$ generates polarization when stressed

Thin film **advantage**

Bottom electrode $\rightarrow$ ZnO ac
Easy to interface with electronics

Strongest piezoelectric response when stress is aligned with **polar C-axis**

- Largest net polarization caused from applying pressure "vertically"
- Applying pressure "laterally" is less effective due to lattice spacing



Project Goal

Fabricate and characterize a **ZnO thin-film piezoelectric pressure sensor** and **quantify** its **electrical output** under controlled loading.

Film Growth

Final Parameters:

FTO covered glass slab (25 mm x 25 mm) as substrate

Cleaned each target for 2000 pulses

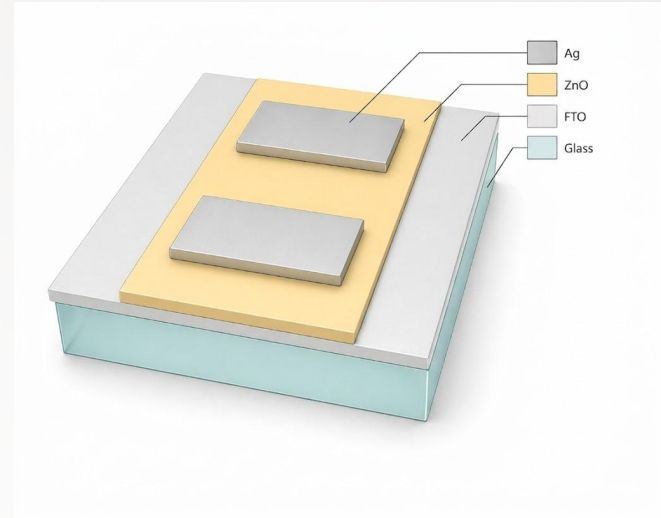
ZnO grown in 5 mtorr O_2 on low for 20,000 pulses

Annealed for 1 hour at 500 °C in heat oven

Ag grown in vacuum for 10,000 pulses with a two rectangle cast

Ag paint on some devices to improve probe contact

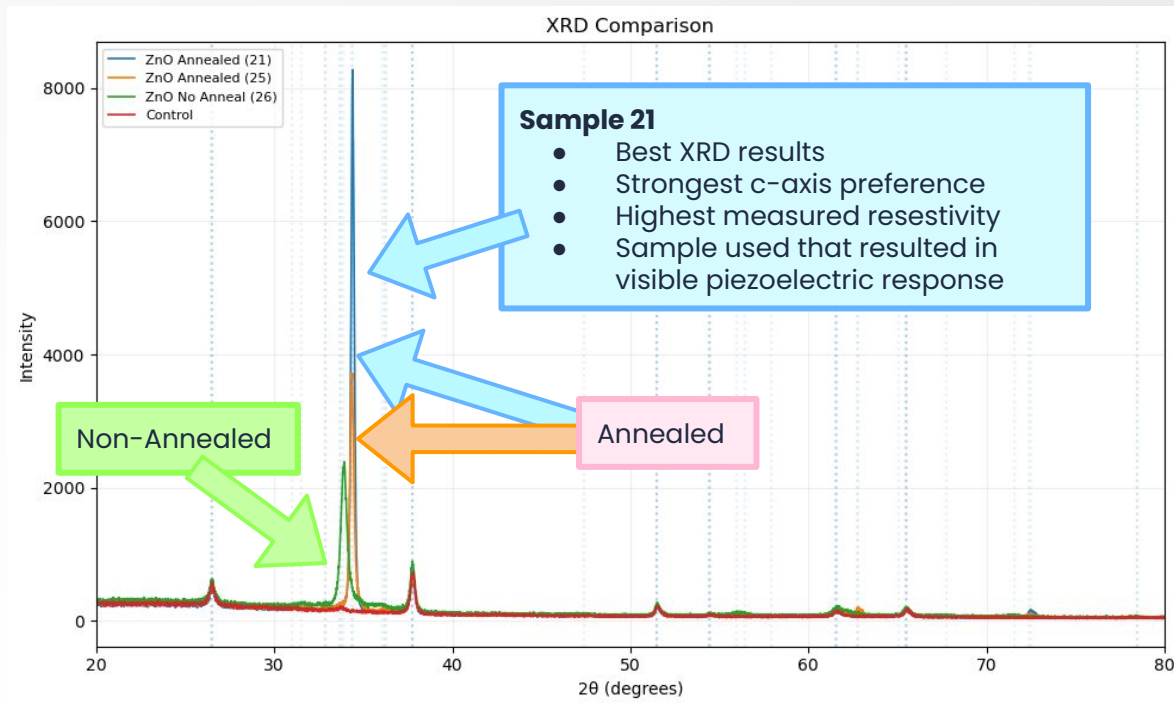
Device Diagram:



XRD Results:

Summary:

Annealed ZnO samples had more consistent and more intense peaks at desired c-axis orientation [0,0,2]





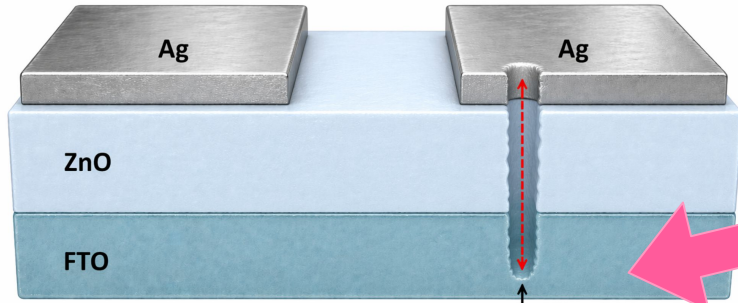
Results



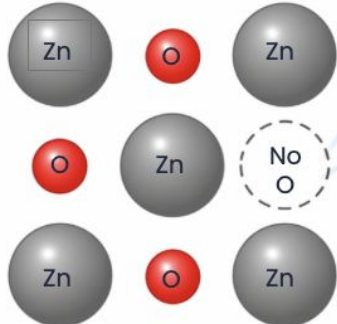
Resistivity

Meth

Obse



Pinhole short
(Ag pinhole contacting FTO)



Free electrons

er resistance

l = 107k ohms

pe 27 ohms

ystal quality,
connection, etc.

il (401)

Oxygen Vacancy →
Free electrons →
n-type semiconductor →
lower resistivity

Potential

Pin

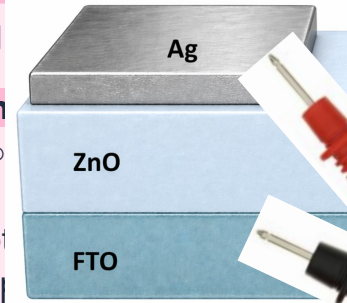
Noi
imp

shorts:

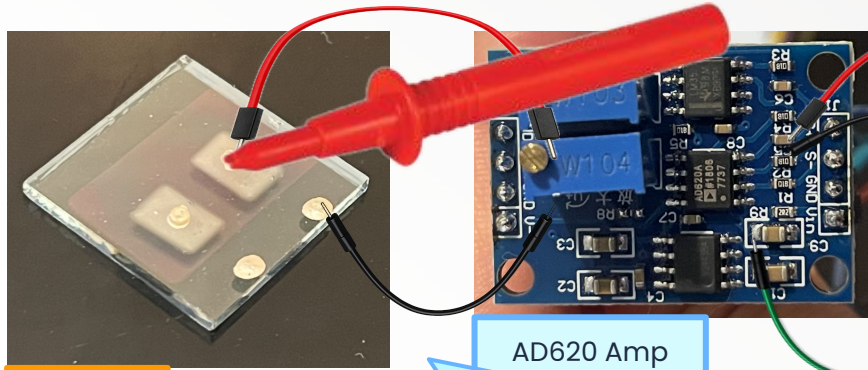
Candidates: grain-b
oxygen-vacancy, pa
defects (ex. density v

Future:

- anneal for **longer** than one hour so that it has more time to fill oxygen-vacancys
- PLD at **higher** oxygen levels so oxygen-vacancies are less likely to form

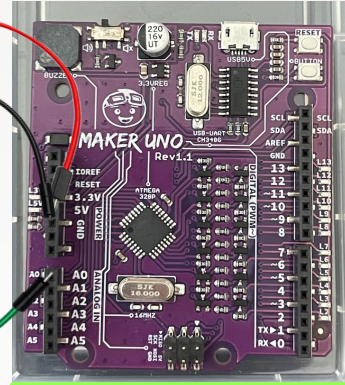


Voltage Measurement Method



Sample

AD620 Amp



Arduino Uno (10-bit ADC)



Computer

Used our 107k ohm sample.
(Sample 21)

- multiplies our signal by **62x** before measurement
- differential input **rejects** 60 Hz **ambient noise** by a factor of 100,000.

An oscilloscope scope does neither

Noise Floor:

- 200–500 μV at sensor input
- Note: minimum in oscilloscope is 1mV

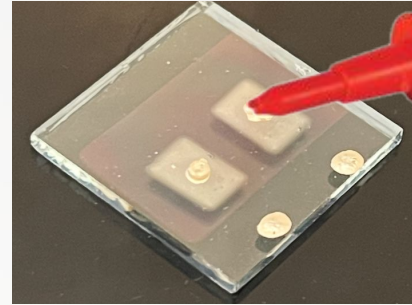
Pressing down:

- Plastic insulating tip is used to apply pressure on the order of 10^2 Pa – 10^3 Pa
- **Signal:** 100–500 μV at sensor input

Signal and Mechanical Force Application

Single Tap :

- Creates a signal of around $\sim 100\text{--}500\ \mu\text{V}$
- Well below noise floor for multi-meter and oscilloscope, within the noise of the AD620 setup
- Does not indicate non-piezoelectric behavior but measurement gets lost in the noise



Rythmic/Cyclical Taps:

- Same signal amplitude as a single tap
- Rhythmic tapping at $\sim 2\text{Hz}$
- Pressure applied in a cyclic fashion does yield **coinciding changes in voltage**
- Cyclical spikes can be differentiated from random noise fluctuations
- Signal is still close to threshold so quantitative results were not made yet



Discussion

Initial Project Goal: Fabricate and characterize a **ZnO thin-film piezoelectric pressure sensor** and **quantify** its **electrical output** under controlled loading.

Success:

- Established ideal growth conditions using PLD and annealing to grow ZnO with the **ideal crystal orientation** (002)
- Created thin film devices where **resistance measurements** provided early insight into device quality
- **Measured potential differences** across thin film electrodes associated with applied pressure = **visible piezoelectric response**

Long-Term Goals

Post ZnO Sensor Film Growth:

- Most Piezoelectric sensors used today are **lead-based**. There are new regulations to **phase these out** and ZnO is the leading **lead-free** alternative
 - More infrastructure and money is backing ZnO pressure sensors
- Growing ZnO films using PLD offers a **cheap** method of manufacturing many pressure sensing devices
- **Affordable pressure sensors** have many applications including
 - **Robotics**
 - **Wearable Health Devices**
 - **Altitude measurements**



Future Timeline

(how we will continue with **your** funding)

Reduce shorts + leakage
(minimize pinhole conduction paths)

01



Increase ZnO resistivity
(MΩ)

02



Refine annealing/PLD growth

03

04



Use calibrated loading (use indentors)

05



Lower measurement noise (shielding or amplification)

06

Quantify voltage + pressure (linearity and repeatability)

RESOURCES

- Thank you: Dr. Rene Lopez, Dr. Shane Brogan, David Stilwell

Sikarwar, S., Satyendra, Singh, S. *et al.* Review on pressure sensors for structural health monitoring. *Photonic Sens* 7, 294–304 (2017). <https://doi.org/10.1007/s13320-017-0419-z>

Vishniakou, Siarhei & Chen, Renjie & Ro, Yun Goo & Brennan, Christopher & Levy, Cooper & Yu, Edward & Dayeh, Shadi. (2018). Improved Performance of Zinc Oxide Thin Film Transistor Pressure Sensors and a Demonstration of a Commercial Chip Compatibility with the New Force Sensing Technology. *Advanced Materials Technologies*. 3. 1700279. 10.1002/admt.201700279.

Silva, L. L., Monteiro, P. C., Savi, M. A. and Netto, T. A. (2013) “Effect of the piezoelectric hysteretic behavior on the vibration-based energy harvesting”, *Journal of Intelligent Material Systems and Structures*, Vol. 24(10), pp. 1285

Almassri, Ahmed & Wan Hasan, W. & Ahmad, Siti & Ishak, Asnor & Mohamad Ghazali, Aina Mardhiyah. (2015). Pressure Sensor: State of the Art, Design, and Application for Robotic Hand. *Journal of Sensors*. 2015. 12. 10.1155/2015/846487.

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Questions?

